

**Search Notes**

Application/Control No.

10/676,258

Examiner

B. Chen

Applicant(s)/Patent under  
Reexamination

MIYANO ET AL.

Art Unit

1762

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
east	2/7/2006	BC